Supporting Information

Thermal Diffusion of Fullerene Acceptors Changes Morphology of Planar Heterojunctions

Yuri Kim*, and Tack Ho Lee†

Graduate Department of Chemical Materials, Institute for Plastic Information and Energy Materials, Sustainable Utilization of Photovoltaic Energy Research Center, Pusan National University, Busan 46241 , Republic of Korea.

†Corresponding Author: Tack Ho Lee
E-mail: tackho@pusan.ac.kr
Tel: +82-51-510-2682

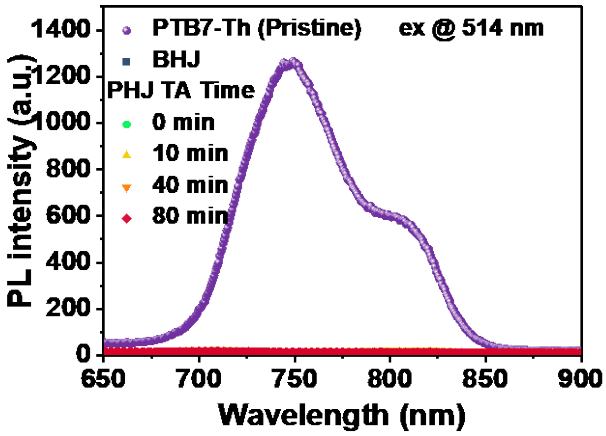

Figure S1. PL spectra of the BHJ and PHJ films as a function of thermal annealing time (100°C) in comparison with the pristine PTB7-Th film.

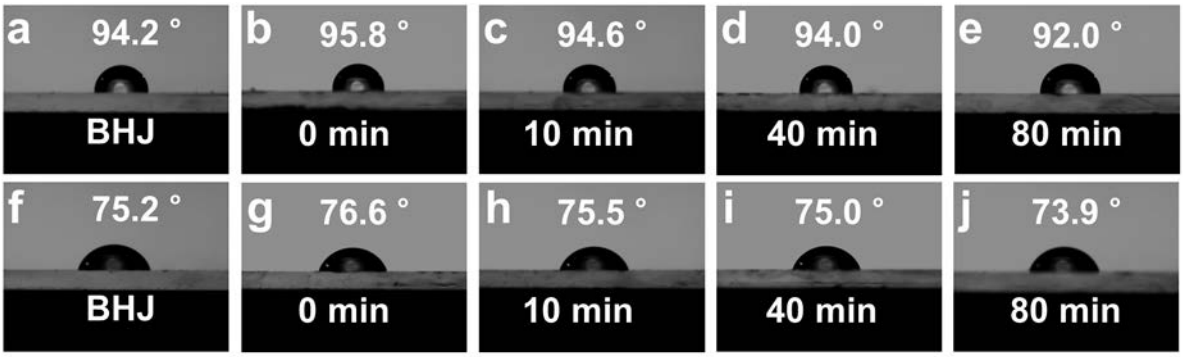

Figure S2. Contact angle of (a~e) water and (f~j) ethylene glycol (EG) drop images of (a, f) BHJ device and (b~e, g~j) PHJ devices as a function of thermal annealing time.

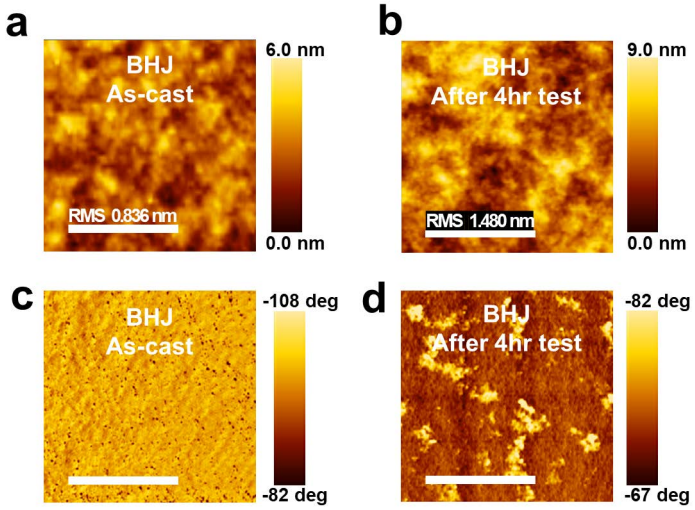

Figure S3. AFM (a, b) height and (c, d) phase images of BHJ film (a, c) before and (b, d) after a 4hr thermal stability test (scale bar: 1 μm).

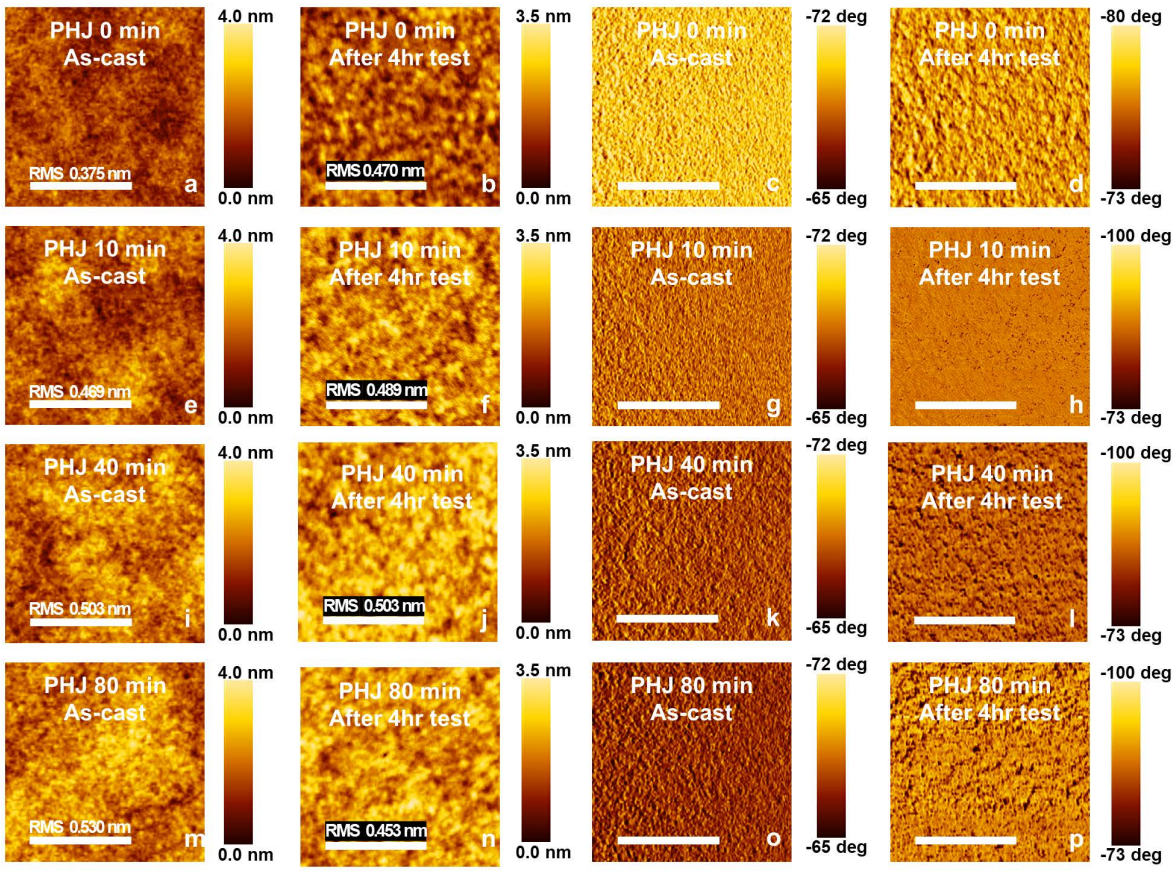

Figure S4. AFM (a, b, e, f, i, j, m, n) height and (c, d, g, h, k, l, o, p) phase images of (a-d) 0, (e- h) 10, (i-l) 40, (m-p) 80 min annealed PHJ film (a, c, e, g, i, k, m, o) before and (b, d, f, h, j, l, n, p) after a 4hr thermal stability test (scale bar: 1 μm).